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| Notice of References Cited | Application/Control No. 10/722,650 | Applicant(s)/Patent Under Reexamination MIKKOLA ET AL | |
| | Examiner Tan Ho | Art Unit 2821 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-4,827,266 | 05-1989 | Sato et al. | 343/700MS |
| | B | US-5,966,097 A | 10-1999 | Fukasawa et al. | 343/700MS |
| | C | US-6,480,155 B1 | 11-2002 | Eggleston, Steve | 343/700MS |
| | D | US-6,535,170 B2 | 03-2003 | Sawamura et al. | 343/702 |
| | E | US-6,657,593 B2 | 12-2003 | Nagumo et al. | 343/700MS |
| | F | US-6,657,595 B1 | 12-2003 | Phillips et al. | 343/702 |
| | G | US-6,819,287 B2 | 11-2004 | Sullivan et al. | 343/700MS |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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